

**Amendments to the Specification:**

Please replace the first paragraph on page 1 with the following amended paragraph:

This application claims the benefit of U.S. Provisional Application No. 60/422,117 filed October 30, 2002, titled "Method and Apparatus for Testing Asynchronous Set/Reset Faults in a Scan-Based Integrated Circuit", which is hereby incorporated by reference.

This application is a continuation-in-part of Wang et al application Serial No. 10/067,372 (Pub. No. 202/0120896) titled "Multiple-Capture DFT System for Detecting or Locating Crossing Clock-Domain Faults During Self-Test or Scan-Test" filed February 7, 2002.